

Search Notes

Application/Control No.

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Examiner

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Applicant(s)/Patent under
Reexamination

FENN, DAVID

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
53	329.3 372.6 374.8 374.9 375.6	7/11/2007	LH
53	477 485 486	7/11/2007	LH
53	487 289 290	7/11/2007	LH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR